

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	2	("3251222").PN.	US-PGPU B; USPAT; EPO; JPO; DERWENT	OR	OFF	2005/04/18 08:17
L4	0	3 and resistance	US-PGPU B; USPAT; EPO; JPO; DERWENT	OR	ON	2005/04/18 08:16
L5	1	3 and element	US-PGPU B; USPAT; EPO; JPO; DERWENT	OR	ON	2005/04/18 08:17
L6	0	3 and piezo\$6	US-PGPU B; USPAT; EPO; JPO; DERWENT	OR	ON	2005/04/18 08:17
L7	112825	"73"/\$7.ccls.	USPAT	OR	ON	2005/04/18 08:32
L8	6285	L7 and ((force pressure piezoresist\$6) near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).ti.	USPAT	OR	ON	2005/04/18 08:33

L9	44	8 and (piezoresistive and (force near surface transmission)))	USPAT	OR	ON	2005/04/18 09:09
L10	16	8 and (piezoresistive and (force near surface block))	USPAT	OR	ON	2005/04/18 08:40
L11	138	8 and (piezoresistive and (force near surface (block member receive surface transmission)))	USPAT	OR	ON	2005/04/18 08:40
L12	51	11 and electrode	USPAT	OR	ON	2005/04/18 08:41
L13	41	12 not 10	USPAT	OR	ON	2005/04/18 08:41
L14	11	("5297438").URPN.	USPAT	OR	ON	2005/04/18 08:49
L39	180	8 and (piezoresistive and (second third another couple pair plurality multiple) near substrate semiconductor silicon))	USPAT	OR	ON	2005/04/18 09:11
L40	95	8 and (piezoresistive and (second third another couple pair plurality multiple) near substrate)	USPAT	OR	ON	2005/04/18 09:11
L41	25	40 and electrode.clm.	USPAT	OR	ON	2005/04/18 09:14
L42	42	40 and electrode	USPAT	OR	ON	2005/04/18 09:14
L43	25	41 and electrode	USPAT	OR	ON	2005/04/18 09:15
S1	2	("1930905" "2137852").PN.	USPAT	OR	ON	2004/11/03 08:27
S2	14	"4546658".URPN.	USPAT	OR	ON	2004/11/03 08:27

S3	2	("5578766").PN.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T	OR	OFF	2004/11/03 08:52
S4	2	("6450040").PN.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T	OR	OFF	2004/11/03 09:11
S5	9	("3145563" "3251222" "3355935" "3582690" "3585415" "3761784" "4480488" "5770803" "5886543").PN.	USPAT	OR	ON	2004/11/03 08:52
S6	4	"3145563".URPN.	USPAT	OR	ON	2004/11/03 09:07
S7	8	((("6091022") or ("5869766") or ("5760675") or ("5939817") or ("4701660") or ("3088323") or ("4556814") or ("4419598"))).PN.	USPAT; USOCR	OR	OFF	2004/11/03 09:20
S8	7	"4419598".URPN.	USPAT	OR	ON	2004/11/03 09:15
S9	6	("2311617" "3283590" "3417322" "3492513" "3739201" "3805601"). PN.	USPAT	OR	ON	2004/11/03 09:17
S10	89951	"310"/\$7.ccls.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/03 09:20

S11	431	S10 and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/03 09:21
S12	51	S11 and (semiconductor substrate).clm.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/03 09:25
S13	19	S12 and electrode.clm.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/03 09:26
S14	19	("2408816" "3714476" "3801838" "3948089" "4480488" "4512431" "4604544" "4816713" "5371472" "5537883" "5682000" "5739626" "5747671" "5777231" "5777239" "5852245" "5886456" "6271621" "6396200").PN.	USPAT	OR	ON	2004/11/03 09:35
S15	0	"6617764".URPN.	USPAT	OR	ON	2004/11/03 09:39
S16	2	("4546658").PN.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T	OR	OFF	2004/11/03 11:18

S17	1	S16 and (substrate semiconductor silicon)	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/03 11:19
S19	311	((73/760,763,774,781, 777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/03 09:20
S20	56	((73/760,763,774,781, 777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and (semiconductor substrate).clm.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/03 09:25
S21	16	((73/760,763,774,781, 777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and (semiconductor substrate).clm.) and electrode.clm.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/03 09:26

S22	13	(((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and (semiconductor substrate).clm.) and electrode.clm.) and current	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 09:41
S23	6	(((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and (semiconductor substrate).clm.) and electrode.clm.) and current.clm.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 09:49
S24	7	("3351786" "4320664" "4703658" "4771639" "4833929" "4993266" "5142914").PN.	USPAT	OR	ON	2004/11/02 09:45
S25	3	"5349873".URPN.	USPAT	OR	ON	2004/11/02 09:48

S26	7	((((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.) and (semiconductor substrate).clm.) and electrode.clm.) and current) not (((((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).clm.) and (semiconductor substrate).clm.) and electrode.clm.) and current.clm.)	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 10:03
S27	10	((("5341688") or ("4833929") or ("4680606") or ("4419598"))).PN.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T	OR	OFF	2004/11/02 10:04
S28	4	((("5341688") or ("4833929") or ("4680606") or ("4419598"))).PN.) and current	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 11:18

S29	175813	kabushiki.as.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 11:19
S30	2438	kabushiki.as. and (force pressure transducer).ti.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 11:20
S31	124	(kabushiki.as. and (force pressure transducer).ti.) and semiconductor.ab.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 11:20
S32	150	(kabushiki.as. and (force pressure transducer).ti.) and electrode.ab.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 11:20
S33	28	((kabushiki.as. and (force pressure transducer).ti.) and semiconductor.ab.) and electrode.ab.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 11:42
S34	7	("3351786" "4320664" "4703658" "4771639" "4833929" "4993266" "5142914").PN.	USPAT	OR	ON	2004/11/02 11:27
S35	2	("3149488" "4833929"). PN.	USPAT	OR	ON	2004/11/02 11:28
S36	19	"4993266".URPN.	USPAT	OR	ON	2004/11/03 11:18

S37	2	("4993266").PN.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T	OR	OFF	2004/11/02 12:05
S38	105	((73/760,763,774,781, 777,862.381,862.474,862. 68,862.621).CCLS.) and electrode near5 ((top face end oppos\$5) and (bottom face other end oppos\$5))	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 12:06
S39	40	((((73/760,763,774,781, 777,862.381,862.474,862. 68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and electrode near5 ((top face end oppos\$5) and (bottom face other end oppos\$5))	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 12:59
S40	16	(((((73/760,763,774,781, 777,862.381,862.474,862. 68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and (semiconductor substrate).clm.) and electrode near5 ((top face end oppos\$5) and (bottom face other end oppos\$5))	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 12:07

S41	24	<p>(((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and electrode near5 ((top face end oppos\$5) and (bottom face other end oppos\$5))) NOT (((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and (semiconductor substrate).clm.) and electrode near5 ((top face end oppos\$5) and (bottom face other end oppos\$5)))</p>	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	ON	2004/11/02 13:01
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S42	6	(((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and electrode near5 ((top face end oppos\$5) and (bottom face other end oppos\$5))) NOT (((73/760,763,774,781,777,862.381,862.474,862.68,862.621).CCLS.) and (force near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)). clm.) and (semiconductor substrate).clm.) and electrode near5 ((top face end oppos\$5) and (bottom face other end oppos\$5)))) and (semiconductor)	US-PGPU B; USPAT; EPO; JPO; DERWENT	OR	ON	2004/11/03 08:50
S43	14	"4546658".URPN.	USPAT	OR	ON	2004/11/02 13:06
S44	19	("3614485" "3634787" "4050530" "4144747" "4215570" "4294105" "4372173" "4546658" "4642508" "4789804" "5023503" "5232063" "5362929" "5684276" "5852229" "5869763" "5946795" "5962786" "6080939").PN.	USPAT	OR	ON	2004/11/02 13:09
S46	112825	"73"/\$7.ccls.	USPAT	OR	ON	2005/04/17 11:54

S47	6285	S46 and ((force pressure piezoresist\$6) near3 (sens\$4 evaluat\$5 estimat\$5 cell rate comput\$5 detect\$4 test\$4 meter gauge transducer measur\$4 indicat\$4 identif\$4 monitor\$4 determina\$4)).ti.	USPAT	OR	ON	2005/04/17 12:41
S48	830	S47 and (substrate)	USPAT	OR	ON	2005/04/17 12:00
S49	371	S48 and (electrode)	USPAT	OR	ON	2005/04/17 12:00
S50	4	S49 and (current and voltage) near6 (path direction)	USPAT	OR	ON	2005/04/17 12:08
S51	27	S49 and (current) near3 (path direction)	USPAT	OR	ON	2005/04/17 12:08
S52	16	S51 and (voltage) near3 (output)	USPAT	OR	ON	2005/04/17 12:35
S53	17	S49 and ((voltage) near3 (output)).clm.	USPAT	OR	ON	2005/04/17 12:35
S54	11	S53 not S52	USPAT	OR	ON	2005/04/17 12:35
S55	5	S53 and piezoresist\$6	USPAT	OR	ON	2005/04/17 12:48
S56	3	("3145563").PN.	US-PGPU B; USPAT; EPO; JPO; DERWEN T	OR	OFF	2005/04/17 12:48
S57	4	("3145563").URPN.	USPAT	OR	ON	2005/04/17 12:48
S58	6	("4833929").URPN.	USPAT	OR	ON	2005/04/17 12:58
S59	7	("3145563" "3149488" "3251222" "4406992").PN.	US-PGPU B; USPAT; USOCR	OR	ON	2005/04/17 12:59

S60	6	("3251222").URPN.	USPAT	OR	ON	2005/04/18 08:16
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